Quad Bus Buffer

with 3-State Control Inputs

The MC74VHC126 is a high speed CMOS quad bus buffer fabricated with silicon gate CMOS technology. It achieves noninverting high speed operation similar to equivalent Bipolar Schottky TTL while maintaining CMOS low power dissipation.

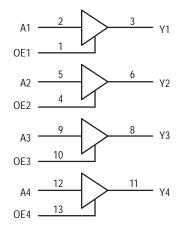
The MC74VHC126 requires the 3–state control input (OE) to be set Low to place the output into high impedance.

The internal circuit is composed of three stages, including a buffer output which provides high noise immunity and stable output. The inputs tolerate voltages up to 7V, allowing the interface of 5V systems to 3V systems.

- High Speed: tpD = 3.8ns (Typ) at $V_{CC} = 5V$
- Low Power Dissipation: $I_{CC} = 4\mu A$ (Max) at $T_A = 25$ °C
- High Noise Immunity: V_{NIH} = V_{NIL} = 28% V_{CC}
- Power Down Protection Provided on Inputs
- Balanced Propagation Delays
- Designed for 2V to 5.5V Operating Range
- Low Noise: VOLP = 0.8V (Max)
- Pin and Function Compatible with Other Standard Logic Families
- Latchup Performance Exceeds 300mA
- ESD Performance: HBM > 2000V; Machine Model > 200V
- Chip Complexity: 72 FETs or 18 Equivalent Gates

LOGIC DIAGRAM

Active-High Output Enables



FUNCTION TABLE

VHC126					
Inp	outs	Output			
Α	OE	Υ			
Н	Н	Н			
L	Н	L			
X	L	Z			



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14-LEAD SOIC D SUFFIX CASE 751A 14-LEAD TSSOP DT SUFFIX CASE 948G



14-LEAD SOIC EIAJ M SUFFIX CASE 965

PIN CONNECTION AND MARKING DIAGRAM (Top View)

OE1	1 •	14	v _{cc}
A1 [2	13	0E4
Y1 🛭	3	12	A4
OE2	4	11	Y4
A2 [5	10	0E3
Y2 [6	9	A 3
GND [7	8	Y3

For detailed package marking information, see the Marking Diagram section on page 5 of this data sheet.

ORDERING INFORMATION

Device	Package	Shipping		
MC74VHC126D	SOIC	55 Units/Rail		
MC74VHC126DT	TSSOP	96 Units/Rail		
MC74VHC126M	SOIC EIAJ	50 Units/Rail		

MAXIMUM RATINGS*

Symbol	Parameter		Value	Unit
VCC	DC Supply Voltage	- 0.5 to + 7.0	V	
V _{in}	DC Input Voltage	- 0.5 to + 7.0	V	
V _{out}	DC Output Voltage	- 0.5 to V _{CC} + 0.5	V	
ΙΙΚ	Input Diode Current	- 20	mA	
lok	Output Diode Current		± 20	mA
l _{out}	DC Output Current, per Pin		± 25	mA
ICC	DC Supply Current, V _{CC} and GND Pins		± 50	mA
PD	Power Dissipation in Still Air, SOIC TSSO	500 450	mW	
T _{stg}	Storage Temperature		- 65 to + 150	°C

^{*} Absolute maximum continuous ratings are those values beyond which damage to the device may occur. Exposure to these conditions or conditions beyond those indicated may adversely affect device reliability. Functional operation under absolute—maximum—rated conditions is not implied.

RECOMMENDED OPERATING CONDITIONS

Symbol	Parameter		Min	Max	Unit
VCC	DC Supply Voltage	2.0	5.5	V	
V _{in}	DC Input Voltage	0	5.5	V	
V _{out}	DC Output Voltage		0	VCC	V
TA	Operating Temperature, All Package T	ypes	- 40	+ 85	°C
t _r , t _f	Input Rise and Fall Time	/ _{CC} = 3.3V ±0.3V / _{CC} =5.0V ±0.5V	0	100 20	ns/V

DC ELECTRICAL CHARACTERISTICS

			VCC	1	A = 25°	2	T _A ≤	85°C	T _A ≤ '	T _A ≤ 125°C	
Symbol	Parameter	Test Conditions	(V)	Min	Тур	Max	Min	Max	Min	Max	Unit
V _{IH}	Minimum High–Level Input Voltage		2.0 3.0 4.5 5.5	1.5 2.1 3.15 3.85			1.5 2.1 3.15 3.85		1.5 2.1 3.15 3.85		V
V _{IL}	Maximum Low–Level Input Voltage		2.0 3.0 4.5 5.5			0.5 0.9 1.35 1.65		0.5 0.9 1.35 1.65		0.5 0.9 1.35 1.65	V
VOH	Minimum High-Level Output Voltage VIN = VIH or VIL	V _{IN} = V _{IH} or V _{IL} I _{OH} = -50μA	2.0 3.0 4.5	1.9 2.9 4.4	2.0 3.0 4.5		1.9 2.9 4.4		1.9 2.9 4.4		V
		V _{IN} = V _{IH} or V _{IL} I _{OH} = -4mA I _{OH} = -8mA	3.0 4.5	2.58 3.94			2.48 3.80		2.34 3.66		V
VOL	Maximum Low–Level Output Voltage V _{IN} = V _{IH} or V _{IL}	V _{IN} = V _{IH} or V _{IL} I _{OL} = 50μA	2.0 3.0 4.5		0.0 0.0 0.0	0.1 0.1 0.1		0.1 0.1 0.1		0.1 0.1 0.1	V
		V _{IN} = V _{IH} or V _{IL} I _{OL} = 4mA I _{OL} = 8mA	3.0 4.5			0.36 0.36		0.44 0.44		0.52 0.52	V
loz	Maximum 3–State Leakage Current	$V_{IN} = V_{IH} \text{ or } V_{IL}$ $V_{OUT} = V_{CC} \text{ or GND}$	5.5			±0.25		±2.5		±2.5	μΑ

This device contains protection circuitry to guard against damage due to high static voltages or electric fields. However, precautions must be taken to avoid applications of any voltage higher than maximum rated voltages to this high–impedance circuit. For proper operation, V_{in} and V_{out} should be constrained to the range GND \leq (V_{in} or V_{out}) \leq V_{CC} .

Unused inputs must always be tied to an appropriate logic voltage level (e.g., either GND or V_{CC}). Unused outputs must be left open.

[†]Derating — SOIC Packages: – 7 mW/°C from 65° to 125°C TSSOP Package: – 6.1 mW/°C from 65° to 125°C

III	N	Maximum Input Leakage Current	V _{IN} = 5.5V or GND	0 to 5.5		±0.1	±1.0	±1.0	μΑ
Ic	CC	Maximum Quiescent Supply Current	$V_{IN} = V_{CC}$ or GND	5.5		4.0	40	40	μΑ

AC ELECTRICAL CHARACTERISTICS (Input $t_f = t_f = 3.0 \text{ns}$)

				1	T _A = 25°(2	T _A = ≤	≤ 85°C	T A = ≤	125°C	
Symbol	Parameter	Test Condi	tions	Min	Тур	Max	Min	Max	Min	Max	Unit
tPLH, tPHL	Maximum Propagation Delay,	V _{CC} = 3.3 ± 0.3V	$C_L = 15pF$ $C_L = 50pF$		5.6 8.1	8.0 11.5	1.0 1.0	9.5 13.0	1.0 1.0	12.0 15.0	ns
	A to Y	V _{CC} = 5.0 ± 0.5V	$C_L = 15pF$ $C_L = 50pF$		3.8 5.3	5.5 7.5	1.0 1.0	6.5 8.5	1.0 1.0	8.5 10.5	
t _{PZL} , t _{PZH}	Maximum Output Enable Time,	$V_{CC} = 3.3 \pm 0.3 V$ $R_L = 1 k\Omega$	$C_L = 15pF$ $C_L = 50pF$		5.4 7.9	8.0 11.5	1.0 1.0	9.5 13.0	1.0 1.0	11.5 15.0	ns
	OE to Y	$V_{CC} = 5.0 \pm 0.5V$ $R_L = 1k\Omega$	C _L = 15pF C _L = 50pF		3.6 5.1	5.1 7.1	1.0 1.0	6.0 8.0	1.0 1.0	7.5 9.5	
t _{PLZ} , t _{PHZ}	Maximum Output Disable Time,	$V_{CC} = 3.3 \pm 0.3 V$ $R_L = 1 k\Omega$	C _L = 50pF		9.5	13.2	1.0	15.0	1.0	18.0	ns
	OE to Y	$V_{CC} = 5.0 \pm 0.5V$ $R_L = 1k\Omega$	C _L = 50pF		6.1	8.8	1.0	10.0	1.0	12.0	
tOSLH, tOSHL	Output-to-Output Skew	V _{CC} = 3.3 ± 0.3V (Note 1.)	C _L = 50pF			1.5		1.5		1.5	ns
		V _{CC} = 5.0 ± 0.5V (Note 1.)	C _L = 50pF			1.0		1.0		1.0	
C _{in}	Maximum Input Capacitance				4	10		10		10	pF
C _{out}	Maximum Three–State Output Capacitance (Output in High Impedance State)				6						pF

		Typical @ 25°C, V _{CC} = 5.0V	
C _{PD}	Power Dissipation Capacitance (Note 2.)	15	pF

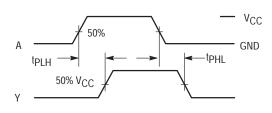
^{1.} Parameter guaranteed by design. $t_{OSLH} = |t_{PLHm} - t_{PLHn}|$, $t_{OSHL} = |t_{PHLm} - t_{PHLn}|$.

NOISE CHARACTERISTICS (Input $t_f = t_f = 3.0$ ns, $C_L = 50$ pF, $V_{CC} = 5.0$ V)

		T _A =	T _A = 25°C	
Symbol	Characteristic	Тур	Max	Unit
VOLP	Quiet Output Maximum Dynamic V _{OL}	0.3	0.8	V
VOLV	Quiet Output Minimum Dynamic V _{OL}	- 0.3	- 0.8	V
VIHD	Minimum High Level Dynamic Input Voltage		3.5	V
VILD	Maximum Low Level Dynamic Input Voltage		1.5	V

^{2.} C_{PD} is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load. Average operating current can be obtained by the equation: $I_{CC(OPR)} = C_{PD} \bullet V_{CC} \bullet f_{in} + I_{CC}/4$ (per buffer). C_{PD} is used to determine the no–load dynamic power consumption; $P_D = C_{PD} \bullet V_{CC}^2 \bullet f_{in} + I_{CC} \bullet V_{CC}$.

SWITCHING WAVEFORMS



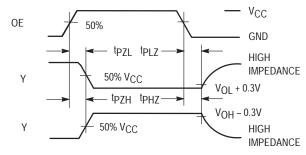
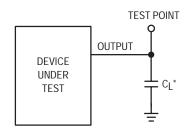
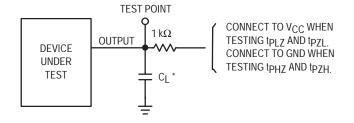


Figure 1.

Figure 2.





*Includes all probe and jig capacitance

Figure 3. Test Circuit

*Includes all probe and jig capacitance

Figure 4. Test Circuit

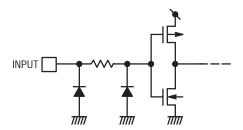
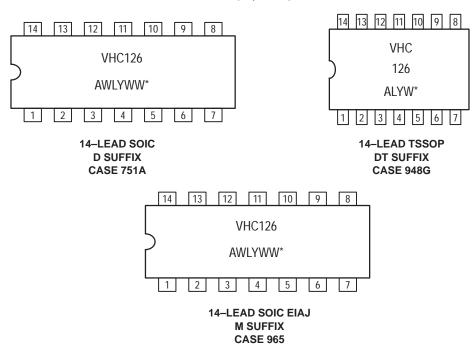


Figure 5. Input Equivalent Circuit

MARKING DIAGRAMS

(Top View)

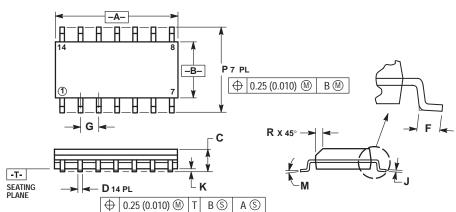


*See Applications Note #AND8004/D for date code and traceability information.

PACKAGE DIMENSIONS

D SUFFIX

PLASTIC SOIC PACKAGE CASE 751A-03 ISSUE F

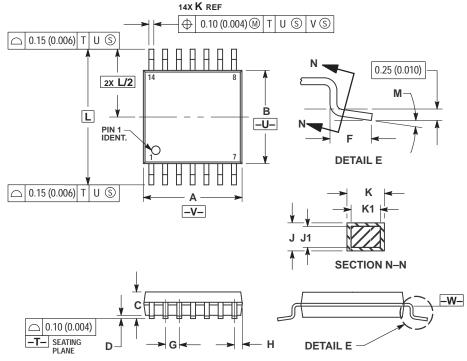


NOTES:

- DIMENSIONING AND TOLERANCING PER ANSI Y14.5M. 1982.
- CONTROLLING DIMENSION: MILLIMETER.
- DIMENSIONS A AND B DO NOT INCLUDE MOLD PROTRUSION.
- MAXIMUM MOLD PROTRUSION 0.15 (0.006) PER SIDE.
- DIMENSION D DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL BE 0.127 (0.005) TOTAL IN EXCESS OF THE D DIMENSION AT MAXIMUM MATERIAL CONDITION.

	MILLIM	ETERS	INC	HES
DIM	MIN	MAX	MIN	MAX
Α	8.55	8.75	0.337	0.344
В	3.80	4.00	0.150	0.157
С	1.35	1.75	0.054	0.068
D	0.35	0.49	0.014	0.019
F	0.40	1.25	0.016	0.049
G	1.27	BSC	0.050	BSC
J	0.19	0.25	0.008	0.009
K	0.10	0.25	0.004	0.009
M	0°	7°	0°	7°
Р	5.80	6.20	0.228	0.244
R	0.25	0.50	0.010	0.019

DT SUFFIX PLASTIC TSSOP PACKAGE CASE 948G-01 **ISSUE O**



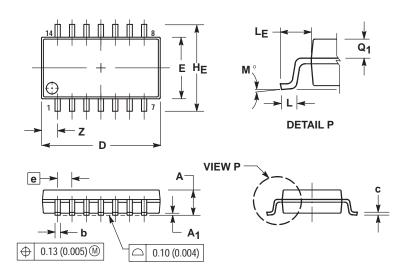
- NOTES:
 1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982. CONTROLLING DIMENSION: MILLIMETER.
- DIMENSION A DOES NOT INCLUDE MOLD FLASH, PROTRUSIONS OR GATE BURRS. MOLD FLASH OR GATE BURRS SHALL NOT EXCEED 0.15 (0.006) PER SIDE
- DIMENSION B DOES NOT INCLUDE INTERLEAD FLASH OR PROTRUSION. INTERLEAD FLASH OR PROTRUSION SHALL NOT EXCEED
- 0.25 (0.010) PER SIDE.
 DIMENSION K DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR
 PROTRUSION SHALL BE 0.08 (0.003) TOTAL IN EXCESS OF THE K DIMENSION AT MAXIMUM MATERIAL CONDITION.
- TERMINAL NUMBERS ARE SHOWN FOR REFERENCE ONLY.
- DIMENSION A AND B ARE TO BE DETERMINED AT DATUM PLANE -W-

	MILLIN	IETERS	INC	HES
DIM	MIN	MAX	MIN	MAX
Α	4.90	5.10	0.193	0.200
В	4.30	4.50	0.169	0.177
С		1.20		0.047
D	0.05	0.15	0.002	0.006
F	0.50	0.75	0.020	0.030
G	0.65	BSC	0.026	BSC
Н	0.50	0.60	0.020	0.024
J	0.09	0.20	0.004	0.008
J1	0.09	0.16	0.004	0.006
K	0.19	0.30	0.007	0.012
K1	0.19	0.25	0.007	0.010
L	6.40	BSC	0.252 BSC	
M	0°	8°	0°	8°

PACKAGE DIMENSIONS

M SUFFIX

PLASTIC SOIC EIAJ PACKAGE CASE 965-01 **ISSUE O**



NOTES:

- 1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
- Y14.5M, 1982.
 2. CONTROLLING DIMENSION: MILLIMETER.
 3. DIMENSIONS D AND E DO NOT INCLUDE
 MOLD FLASH OR PROTRUSIONS AND ARE
 MEASURED AT THE PARTING LINE. MOLD FLASH
- MEASURED AT THE PARTING LINE. MOLD FLASH
 OR PROTRUSIONS SHALL NOT EXCEED 0.15
 (0.006) PER SIDE.

 4. TERMINAL NUMBERS ARE SHOWN FOR
 REFERENCE ONLY.
 5. THE LEAD WIDTH DIMENSION (b) DOES NOT
 INCLUDE DAMBAR PROTRUSION. ALLOWABLE
 DAMBAR PROTRUSION SHALL BE 0.08 (0.003)
 TOTAL IN EXCESS OF THE LEAD WIDTH
 DIMENSION AT MAXIMUM MATERIAL CONDITION.
 DAMBAR CANNOT BE 1.0 COATED ON THE 1.0 WER DAMBAR CANNOT BE LOCATED ON THE LOWER RADIUS OR THE FOOT. MINIMUM SPACE BETWEEN PROTRUSIONS AND ADJACENT LEAD TO BE 0.46 (0.018).

	MILLIMETERS		INCHES	
DIM	MIN	MAX	MIN	MAX
Α		2.05		0.081
Α ₁	0.05	0.20	0.002	0.008
b	0.35	0.50	0.014	0.020
С	0.18	0.27	0.007	0.011
D	9.90	10.50	0.390	0.413
Е	5.10	5.45	0.201	0.215
е	1.27 BSC		0.050 BSC	
HE	7.40	8.20	0.291	0.323
0.50	0.50	0.85	0.020	0.033
LF	1.10	1.50	0.043	0.059
M	0 °	10 °	0 °	10°
Q ₁	0.70	0.90	0.028	0.035
Z		1.42		0.056

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